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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	67MHz
Connectivity	EBI/EMI, I ² C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	62
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3666axi-036

5.4 EEPROM

PSoC EEPROM memory is a byte-addressable nonvolatile memory. The CY8C36 has up to 2 KB of EEPROM memory to store user data. Reads from EEPROM are random access at the byte level. Reads are done directly; writes are done by sending write commands to an EEPROM programming interface. CPU code execution can continue from flash during EEPROM writes. EEPROM is erasable and writable at the row level. The EEPROM is divided into 128 rows of 16 bytes each. The factory default values of all EEPROM bytes are 0.

Because the EEPROM is mapped to the 8051 xdata space, the CPU cannot execute out of EEPROM. There is no ECC hardware associated with EEPROM. If ECC is required it must be handled in firmware.

It can take as much as 20 milliseconds to write to EEPROM or flash. During this time the device should not be reset, or unexpected changes may be made to portions of EEPROM or flash. Reset sources (see [Section 6.3.1](#)) include XRES pin, software reset, and watchdog; care should be taken to make sure that these are not inadvertently activated. In addition, the low voltage detect circuits should be configured to generate an interrupt instead of a reset.

5.5 Nonvolatile Latches (NVLs)

PSoC has a 4-byte array of nonvolatile latches (NVLs) that are used to configure the device at reset. The NVL register map is shown in [Table 5-2](#).

Table 5-2. Device Configuration NVL Register Map

Register Address	7	6	5	4	3	2	1	0
0x00	PRT3RDM[1:0]		PRT2RDM[1:0]		PRT1RDM[1:0]		PRT0RDM[1:0]	
0x01	PRT12RDM[1:0]		PRT6RDM[1:0]		PRT5RDM[1:0]		PRT4RDM[1:0]	
0x02	XRESMEN	DBGEN					PRT15RDM[1:0]	
0x03	DIG_PHS_DLY[3:0]				ECCEN	DPS[1:0]		CFGSPD

The details for individual fields and their factory default settings are shown in [Table 5-3](#).

Table 5-3. Fields and Factory Default Settings

Field	Description	Settings
PRTxRDM[1:0]	Controls reset drive mode of the corresponding IO port. See “Reset Configuration” on page 43. All pins of the port are set to the same mode.	00b (default) - high impedance analog 01b - high impedance digital 10b - resistive pull up 11b - resistive pull down
XRESMEN	Controls whether pin P1[2] is used as a GPIO or as an external reset. See “Pin Descriptions” on page 12, XRES description.	0 (default for 68-pin 72-pin, and 100-pin parts) - GPIO 1 (default for 48-pin parts) - external reset
DBGEN	Debug Enable allows access to the debug system, for third-party programmers.	0 - access disabled 1 (default) - access enabled
CFGSPD	Controls the speed of the IMO-based clock during the device boot process, for faster boot or low-power operation	0 (default) - 12 MHz IMO 1 - 48 MHz IMO
DPS[1:0]	Controls the usage of various P1 pins as a debug port. See “Programming, Debug Interfaces, Resources” on page 65.	00b - 5-wire JTAG 01b (default) - 4-wire JTAG 10b - SWD 11b - debug ports disabled
ECCEN	Controls whether ECC flash is used for ECC or for general configuration and data storage. See “Flash Program Memory” on page 23.	0 - ECC disabled 1 (default) - ECC enabled
DIG_PHS_DLY[3:0]	Selects the digital clock phase delay.	See the TRM for details.

Although PSoC Creator provides support for modifying the device configuration NVLs, the number of NVL erase / write cycles is limited – see [“Nonvolatile Latches \(NVL\)”](#) on page 110.

5.7.3.1 XData Space Access SFRs

The 8051 core features dual DPTR registers for faster data transfer operations. The data pointer select SFR, DPS, selects which data pointer register, DPTR0 or DPTR1, is used for the following instructions:

- MOVX @DPTR, A
- MOVX A, @DPTR
- MOVC A, @A+DPTR
- JMP @A+DPTR
- INC DPTR
- MOV DPTR, #data16

The extended data pointer SFRs, DPX0, DPX1, MXAX, and P2AX, hold the most significant parts of memory addresses during access to the xdata space. These SFRs are used only with the MOVX instructions.

During a MOVX instruction using the DPTR0/DPTR1 register, the most significant byte of the address is always equal to the contents of DPX0/DPX1.

During a MOVX instruction using the R0 or R1 register, the most significant byte of the address is always equal to the contents of MXAX, and the next most significant byte is always equal to the contents of P2AX.

5.7.3.2 I/O Port SFRs

The I/O ports provide digital input sensing, output drive, pin interrupts, connectivity for analog inputs and outputs, LCD, and access to peripherals through the DSI. Full information on I/O ports is found in [I/O System and Routing](#) on page 37.

I/O ports are linked to the CPU through the PHUB and are also available in the SFRs. Using the SFRs allows faster access to a limited set of I/O port registers, while using the PHUB allows boot configuration and access to all I/O port registers.

Each SFR supported I/O port provides three SFRs:

- SFRPRTxDR sets the output data state of the port (where x is port number and includes ports 0–6, 12 and 15).
- The SFRPRTxSEL selects whether the PHUB PRTxDR register or the SFRPRTxDR controls each pin's output buffer within the port. If a SFRPRTxSEL[y] bit is high, the corresponding SFRPRTxDR[y] bit sets the output state for that pin. If a SFRPRTxSEL[y] bit is low, the corresponding PRTxDR[y] bit sets the output state of the pin (where y varies from 0 to 7).
- The SFRPRTxPS is a read only register that contains pin state values of the port pins.

5.7.4 xdata Space

The 8051 xdata space is 24-bit, or 16 MB in size. The majority of this space is not “external”—it is used by on-chip components. See [Table 5-5](#). External, that is, off-chip, memory can be accessed using the EMIF. See [External Memory Interface](#) on page 25.

Table 5-5. XDATA Data Address Map

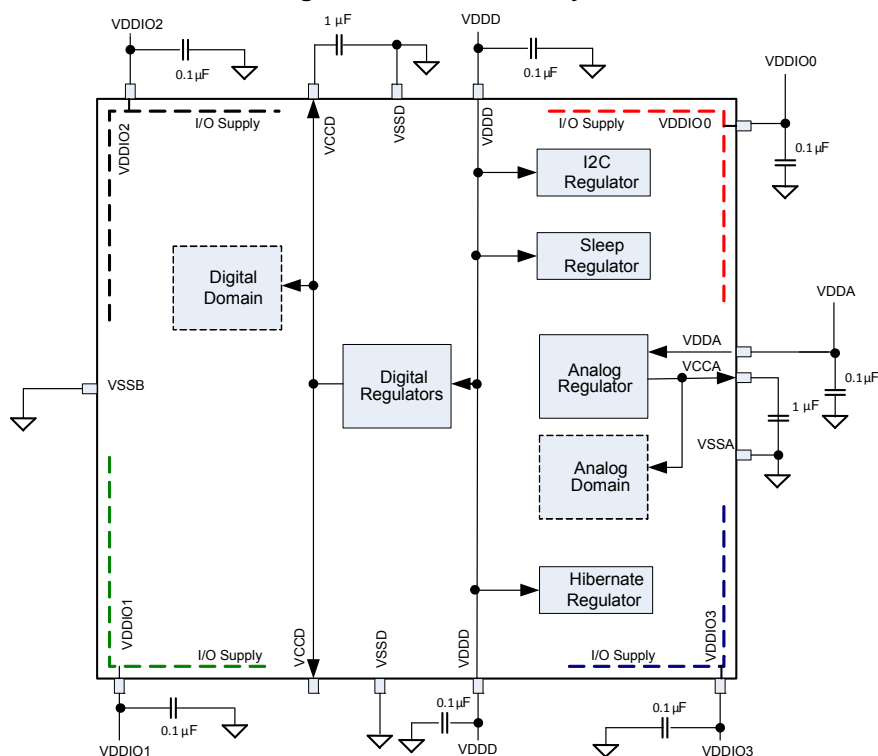
Address Range	Purpose
0x00 0000 – 0x00 1FFF	SRAM
0x00 4000 – 0x00 42FF	Clocking, PLLs, and oscillators
0x00 4300 – 0x00 43FF	Power management
0x00 4400 – 0x00 44FF	Interrupt controller
0x00 4500 – 0x00 45FF	Ports interrupt control
0x00 4700 – 0x00 47FF	Flash programming interface
0x00 4800 – 0x00 48FF	Cache controller
0x00 4900 – 0x00 49FF	I ² C controller
0x00 4E00 – 0x00 4EFF	Decimator
0x00 4F00 – 0x00 4FFF	Fixed timer/counter/PWMs
0x00 5000 – 0x00 51FF	I/O ports control
0x00 5400 – 0x00 54FF	External Memory Interface (EMIF) control registers
0x00 5800 – 0x00 5FFF	Analog Subsystem interface
0x00 6000 – 0x00 60FF	USB controller
0x00 6400 – 0x00 6FFF	UDB Working Registers
0x00 7000 – 0x00 7FFF	PHUB configuration
0x00 8000 – 0x00 8FFF	EEPROM
0x00 A000 – 0x00 A400	CAN
0x00 C000 – 0x00 C800	Digital Filter Block
0x01 0000 – 0x01 FFFF	Digital Interconnect configuration
0x05 0220 – 0x05 02F0	Debug controller
0x08 0000 – 0x08 1FFF	flash ECC bytes
0x80 0000 – 0xFF FFFF	External Memory Interface

6.2 Power System

The power system consists of separate analog, digital, and I/O supply pins, labeled VDDA, VDDD, and VDDIOx, respectively. It also includes two internal 1.8 V regulators that provide the digital (VCCD) and analog (VCCA) supplies for the internal core logic. The output pins of the regulators (VCCD and VCCA) and the

VDDIO pins must have capacitors connected as shown in [Figure 6-4](#). The two VCCD pins must be shorted together, with as short a trace as possible, and connected to a $1\text{-}\mu\text{F} \pm 10\% \times 5\text{R}$ capacitor. The power system also contains a sleep regulator, an I²C regulator, and a hibernate regulator.

Figure 6-4. PSoC Power System



Notes

- The two VCCD pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in [Figure 2-8](#) on page 12.
- It is good practice to check the datasheets for your bypass capacitors, specifically the working voltage and the DC bias specifications. With some capacitors, the actual capacitance can decrease considerably when the DC bias (VDDx or VCCx in [Figure 6-4](#)) is a significant percentage of the rated working voltage.
- You can power the device in internally regulated mode, where the voltage applied to the VDDx pins is as high as 5.5 V, and the internal regulators provide the core voltages. **In this mode, do not apply power to the VCCx pins, and do not tie the VDDx pins to the VCCx pins.**
- You can also power the device in externally regulated mode, that is, by directly powering the VCCD and VCCA pins. In this configuration, the VDDD pins should be shorted to the VCCD pins and the VDDA pin should be shorted to the VCCA pin. The allowed supply range in this configuration is 1.71 V to 1.89 V. After power up in this configuration, the internal regulators are on by default, and should be disabled to reduce power consumption.

6.4.5 Pin Interrupts

All GPIO and SIO pins are able to generate interrupts to the system. All eight pins in each port interface to their own Port Interrupt Control Unit (PICU) and associated interrupt vector. Each pin of the port is independently configurable to detect rising edge, falling edge, both edge interrupts, or to not generate an interrupt.

Depending on the configured mode for each pin, each time an interrupt event occurs on a pin, its corresponding status bit of the interrupt status register is set to “1” and an interrupt request is sent to the interrupt controller. Each PICU has its own interrupt vector in the interrupt controller and the pin status register providing easy determination of the interrupt source down to the pin level.

Port pin interrupts remain active in all sleep modes allowing the PSoC device to wake from an externally generated interrupt.

While level sensitive interrupts are not directly supported; universal digital blocks (UDB) provide this functionality to the system when needed.

6.4.6 Input Buffer Mode

GPIO and SIO input buffers can be configured at the port level for the default CMOS input thresholds or the optional LVTTL input thresholds. All input buffers incorporate Schmitt triggers for input hysteresis. Additionally, individual pin input buffers can be disabled in any drive mode.

6.4.7 I/O Power Supplies

Up to four I/O pin power supplies are provided depending on the device and package. Each I/O supply must be less than or equal to the voltage on the chip’s analog (VDDA) pin. This feature allows users to provide different I/O voltage levels for different pins on the device. Refer to the specific device package pinout to determine VDDIO capability for a given port and pin.

The SIO port pins support an additional regulated high output capability, as described in [Adjustable Output Level](#).

6.4.8 Analog Connections

These connections apply only to GPIO pins. All GPIO pins may be used as analog inputs or outputs. The analog voltage present on the pin must not exceed the VDDIO supply voltage to which the GPIO belongs. Each GPIO may connect to one of the analog global busses or to one of the analog mux buses to connect any pin to any internal analog resource such as ADC or comparators. In addition, select pins provide direct connections to specific analog features such as the high current DACs or uncommitted opamps.

6.4.9 CapSense

This section applies only to GPIO pins. All GPIO pins may be used to create CapSense buttons and sliders^[19]. See the “[CapSense](#)” section on page 63 for more information.

6.4.10 LCD Segment Drive

This section applies only to GPIO pins. All GPIO pins may be used to generate Segment and Common drive signals for direct glass drive of LCD glass. See the “[LCD Direct Drive](#)” section on page 62 for details.

6.4.11 Adjustable Output Level

This section applies only to SIO pins. SIO port pins support the ability to provide a regulated high output level for interface to external signals that are lower in voltage than the SIO’s respective VDDIO. SIO pins are individually configurable to output either the standard VDDIO level or the regulated output, which is based on an internally generated reference. Typically a voltage DAC (VDAC) is used to generate the reference (see [Figure 6-13](#)). The “[DAC](#)” section on page 64 has more details on VDAC use and reference routing to the SIO pins. Resistive pull-up and pull-down drive modes are not available with SIO in regulated output mode.

6.4.12 Adjustable Input Level

This section applies only to SIO pins. SIO pins by default support the standard CMOS and LVTTL input levels but also support a differential mode with programmable levels. SIO pins are grouped into pairs. Each pair shares a reference generator block which, is used to set the digital input buffer reference level for interface to external signals that differ in voltage from VDDIO. The reference sets the pins voltage threshold for a high logic level (see [Figure 6-13](#)). Available input thresholds are:

- $0.5 \times VDDIO$
- $0.4 \times VDDIO$
- $0.5 \times V_{REF}$
- V_{REF}

Typically a voltage DAC (VDAC) generates the V_{REF} reference. “[DAC](#)” section on page 64 has more details on VDAC use and reference routing to the SIO pins.

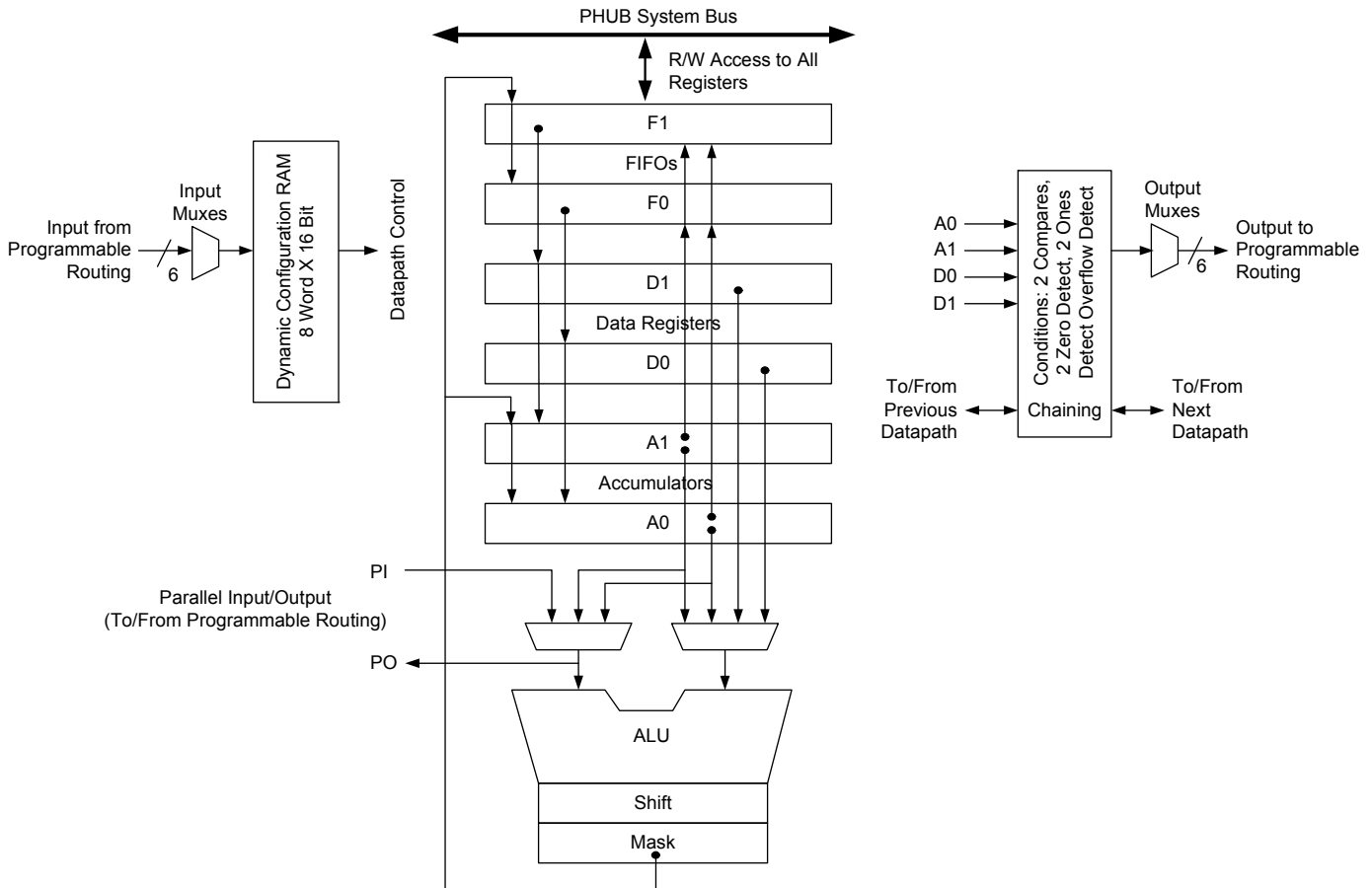
Note

19. GPIOs with opamp outputs are not recommended for use with CapSense

7.2.2 Datapath Module

The datapath contains an 8-bit single cycle ALU, with associated compare and condition generation logic. This datapath block is optimized to implement embedded functions, such as timers, counters, integrators, PWMs, PRS, CRC, shifters and dead band generators and many others.

Figure 7-4. Datapath Top Level



7.2.2.1 Working Registers

The datapath contains six primary working registers, which are accessed by CPU firmware or DMA during normal operation.

Table 7-1. Working Datapath Registers

Name	Function	Description
A0 and A1	Accumulators	These are sources and sinks for the ALU and also sources for the compares.
D0 and D1	Data Registers	These are sources for the ALU and sources for the compares.
F0 and F1	FIFOs	These are the primary interface to the system bus. They can be a data source for the data registers and accumulators or they can capture data from the accumulators or ALU. Each FIFO is four bytes deep.

7.2.2.2 Dynamic Configuration RAM

Dynamic configuration is the ability to change the datapath function and internal configuration on a cycle-by-cycle basis, under sequencer control. This is implemented using the 8-word × 16-bit configuration RAM, which stores eight unique 16-bit wide configurations. The address input to this RAM controls the sequence, and can be routed from any block connected to the UDB routing matrix, most typically PLD logic, I/O pins, or from the outputs of this or other datapath blocks.

ALU

The ALU performs eight general purpose functions. They are:

- Increment
- Decrement
- Add
- Subtract
- Logical AND
- Logical OR
- Logical XOR
- Pass, used to pass a value through the ALU to the shift register, mask, or another UDB register

7.9 Digital Filter Block

Some devices in the CY8C36 family of devices have a dedicated HW accelerator block used for digital filtering. The DFB has a dedicated multiplier and accumulator that calculates a 24-bit by 24-bit multiply accumulate in one bus clock cycle. This enables the mapping of a direct form FIR filter that approaches a computation rate of one FIR tap for each clock cycle. The MCU can implement any of the functions performed by this block, but at a slower rate that consumes MCU bandwidth.

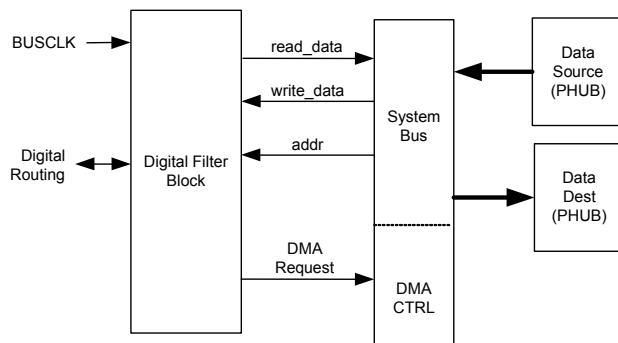
The heart of the DFB is a datapath (DP), which is the numerical calculation unit of the DFB. The DP is a 24-bit fixed-point numerical processor containing a 48-bit multiply and accumulate function (MAC), a multi-function ALU, sample and coefficient data RAMs as well as data routing, shifting, holding and rounding functions.

In the MAC, two 24-bit values can be multiplied and the result added to the 48-bit accumulator in each bus clock cycle. The MAC is the only portion of the DP that is wider than 24 bits. All results from the MAC are passed on to the ALU as 24-bit values representing the high-order 24 bits in the accumulator shifted by one (bits 46:23). The MAC assumes an implied binary point after the most significant bit.

The DP also contains an optimized ALU that supports add, subtract, comparison, threshold, absolute value, squelch, saturation, and other functions. The DP unit is controlled by seven control fields totaling 18 bits coming from the DFB Controller. For more information see the TRM.

The PSoC Creator interface provides a wizard to implement FIR and IIR digital filters with coefficients for LPF, BPF, HPF, Notch and arbitrary shape filters. 64 pairs of data and coefficients are stored. This enables a 64 tap FIR filter or up to 4 16 tap filters of either FIR or IIR formulation.

Figure 7-20. DFB Application Diagram (pwr/gnd not shown)



The typical use model is for data to be supplied to the DFB over the system bus from another on-chip system data source such as an ADC. The data typically passes through main memory or is directly transferred from another chip resource through DMA. The DFB processes this data and passes the result to another on-chip resource such as a DAC or main memory through DMA on the system bus.

Data movement in or out of the DFB is typically controlled by the system DMA controller but can be moved directly by the MCU.

8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

- Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses.
- High resolution Delta-Sigma ADC.
- Up to four 8-bit DACs that provide either voltage or current output.
- Four comparators with optional connection to configurable LUT outputs.
- Up to four configurable switched capacitor/continuous time (SC/CT) blocks for functions that include opamp, unity gain buffer, programmable gain amplifier, transimpedance amplifier, and mixer.
- Up to four opamps for internal use and connection to GPIO that can be used as high current output buffers.
- CapSense subsystem to enable capacitive touch sensing.
- Precision reference for generating an accurate analog voltage for internal analog blocks.

The same opamps and block interfaces are also connectable to an array of resistors which allows the construction of a variety of continuous time functions.

The opamp and resistor array is programmable to perform various analog functions including

- Naked operational amplifier – Continuous mode
- Unity-gain buffer – Continuous mode
- Programmable gain amplifier (PGA) – Continuous mode
- Transimpedance amplifier (TIA) – Continuous mode
- Up/down mixer – Continuous mode
- Sample and hold mixer (NRZ S/H) – Switched cap mode
- First order analog to digital modulator – Switched cap mode

8.5.1 Naked Opamp

The Naked Opamp presents both inputs and the output for connection to internal or external signals. The opamp has a unity gain bandwidth greater than 6.0 MHz and output drive current up to 650 μ A. This is sufficient for buffering internal signals (such as DAC outputs) and driving external loads greater than 7.5 k Ω .

8.5.2 Unity Gain

The Unity Gain buffer is a Naked Opamp with the output directly connected to the inverting input for a gain of 1.00. It has a –3 dB bandwidth greater than 6.0 MHz.

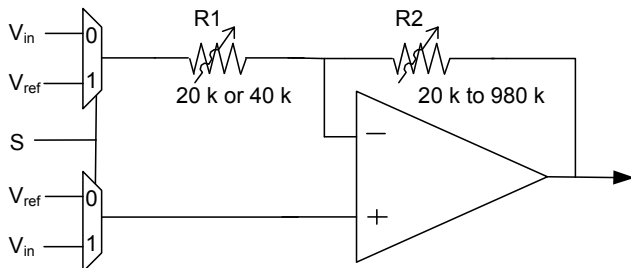
8.5.3 PGA

The PGA amplifies an external or internal signal. The PGA can be configured to operate in inverting mode or noninverting mode. The PGA function may be configured for both positive and negative gains as high as 50 and 49 respectively. The gain is adjusted by changing the values of R1 and R2 as illustrated in Figure 8-8 on page 62. The schematic in Figure 8-8 on page 62 shows the configuration and possible resistor settings for the PGA. The gain is switched from inverting and non inverting by changing the shared select value of the both the input muxes. The bandwidth for each gain case is listed in Table 8-3.

Table 8-3. Bandwidth

Gain	Bandwidth
1	6.0 MHz
24	340 kHz
48	220 kHz
50	215 kHz

Figure 8-8. PGA Resistor Settings



The PGA is used in applications where the input signal may not be large enough to achieve the desired resolution in the ADC, or dynamic range of another SC/CT block such as a mixer. The gain is adjustable at runtime, including changing the gain of the PGA prior to each ADC sample.

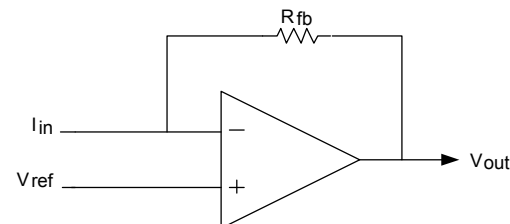
8.5.4 TIA

The Transimpedance Amplifier (TIA) converts an internal or external current to an output voltage. The TIA uses an internal feedback resistor in a continuous time configuration to convert input current to output voltage. For an input current I_{in} , the output voltage is $V_{REF} - I_{in} \times R_{fb}$, where V_{REF} is the value placed on the non inverting input. The feedback resistor R_{fb} is programmable between 20 K Ω and 1 M Ω through a configuration register. Table 8-4 shows the possible values of R_{fb} and associated configuration settings.

Table 8-4. Feedback Resistor Settings

Configuration Word	Nominal R_{fb} (K Ω)
000b	20
001b	30
010b	40
011b	60
100b	120
101b	250
110b	500
111b	1000

Figure 8-9. Continuous Time TIA Schematic



The TIA configuration is used for applications where an external sensor's output is current as a function of some type of stimulus such as temperature, light, magnetic flux etc. In a common application, the voltage DAC output can be connected to the V_{REF} TIA input to allow calibration of the external sensor bias current by adjusting the voltage DAC output voltage.

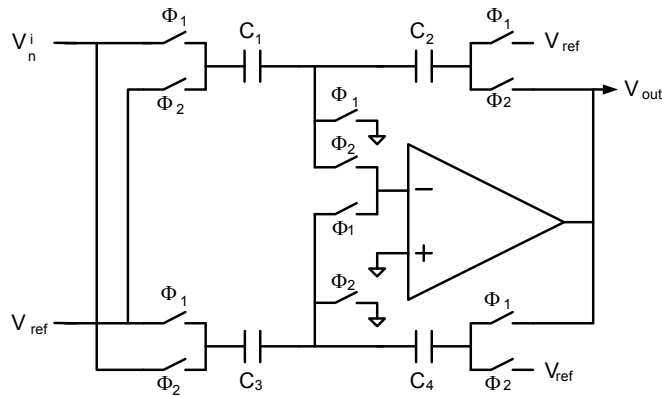
8.6 LCD Direct Drive

The PSoC Liquid Crystal Display (LCD) driver system is a highly configurable peripheral designed to allow PSoC to directly drive a broad range of LCD glass. All voltages are generated on chip, eliminating the need for external components. With a high multiplex ratio of up to 1/16, the CY8C36 family LCD driver system can drive a maximum of 736 segments. The PSoC LCD driver module was also designed with the conservative power budget of portable devices in mind, enabling different LCD drive modes and power down modes to conserve power.

8.11 Sample and Hold

The main application for a sample and hold, is to hold a value stable while an ADC is performing a conversion. Some applications require multiple signals to be sampled simultaneously, such as for power calculations (V and I).

Figure 8-13. Sample and Hold Topology
(Φ_1 and Φ_2 are opposite phases of a clock)



8.11.1 Down Mixer

The SC/CT block can be used as a mixer to down convert an input signal. This circuit is a high bandwidth passive sample network that can sample input signals up to 14 MHz. This sampled value is then held using the opamp with a maximum clock rate of 4 MHz. The output frequency is at the difference between the input frequency and the highest integer multiple of the Local Oscillator that is less than the input.

8.11.2 First Order Modulator – SC Mode

A first order modulator is constructed by placing the SC/CT block in an integrator mode and using a comparator to provide a 1-bit feedback to the input. Depending on this bit, a reference voltage is either subtracted or added to the input signal. The block output is the output of the comparator and not the integrator in the modulator case. The signal is downshifted and buffered and then processed by a decimator to make a delta-sigma converter or a counter to make an incremental converter. The accuracy of the sampled data from the first-order modulator is determined from several factors.

The main application for this modulator is for a low frequency ADC with high accuracy. Applications include strain gauges, thermocouples, precision voltage, and current measurement.

9. Programming, Debug Interfaces, Resources

PSoC devices include extensive support for programming, testing, debugging, and tracing both hardware and firmware. Three interfaces are available: JTAG, SWD, and SWV. JTAG and SWD support all programming and debug features of the device. JTAG also supports standard JTAG scan chains for board level test and chaining multiple JTAG devices to a single JTAG connection.

For more information on PSoC 3 Programming, refer to the [PSoC® 3 Device Programming Specifications](#).

Complete Debug on Chip (DoC) functionality enables full device debugging in the final system using the standard production device. It does not require special interfaces, debugging pods, simulators, or emulators. Only the standard programming connections are required to fully support debug.

The PSoC Creator IDE software provides fully integrated programming and debug support for PSoC devices. The low cost MiniProg3 programmer and debugger is designed to provide full programming and debug support of PSoC devices in conjunction with the PSoC Creator IDE. PSoC JTAG, SWD, and SWV interfaces are compatible with industry standard third party tools.

All DOC circuits are disabled by default and can only be enabled in firmware. If not enabled, the only way to reenale them is to erase the entire device, clear flash protection, and reprogram the device with new firmware that enables DOC. Disabling DOC features, robust flash protection, and hiding custom analog and digital functionality inside the PSoC device provide a level of security not possible with multichip application solutions. Additionally, all device interfaces can be permanently disabled (Device Security) for applications concerned about phishing attacks due to a maliciously reprogrammed device. Permanently disabling interfaces is not recommended in most applications because the you cannot access the device later. Because all programming, debug, and test interfaces are disabled when Device Security is enabled, PSoCs with Device Security enabled may not be returned for failure analysis.

Table 9-1. Debug Configurations

Debug and Trace Configuration	GPIO Pins Used
All debug and trace disabled	0
JTAG	4 or 5
SWD	2
SWV	1
SWD + SWV	3

9.1 JTAG Interface

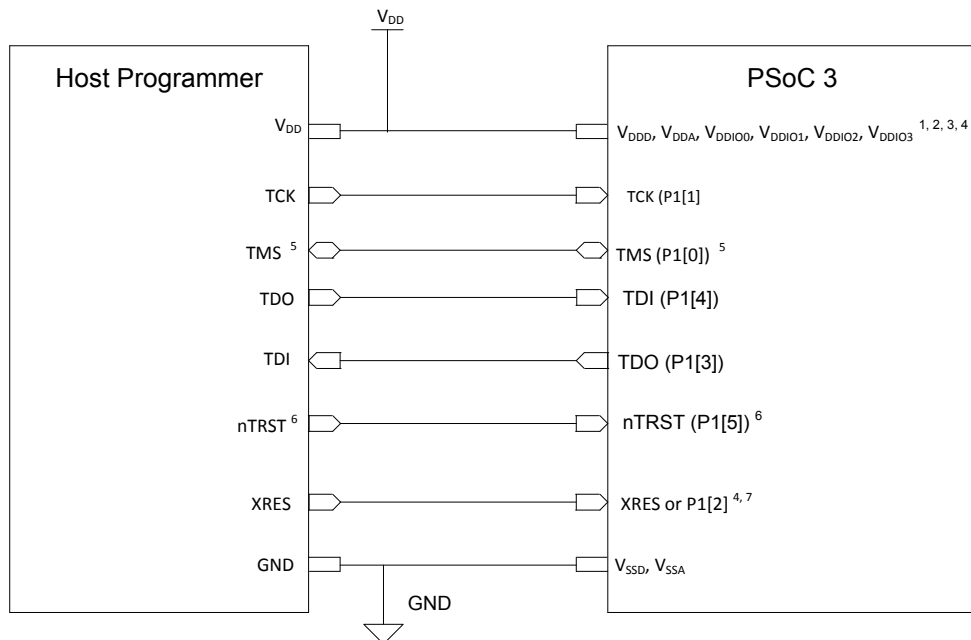
The IEEE 1149.1 compliant JTAG interface exists on four or five pins (the nTRST pin is optional). The JTAG interface is used for programming the flash memory, debugging, I/O scan chains, and JTAG device chaining.

PSoC 3 has certain timing requirements to be met for entering programming mode through the JTAG interface. Due to these timing requirements, not all standard JTAG programmers, or standard JTAG file formats such as SVF or STAPL, can support

PSoC 3 programming. The list of programmers that support PSoC 3 programming is available at <http://www.cypress.com/go/programming>.

The JTAG clock frequency can be up to 14 MHz, or 1/3 of the CPU clock frequency for 8 and 16-bit transfers, or 1/5 of the CPU clock frequency for 32-bit transfers. By default, the JTAG pins are enabled on new devices but the JTAG interface can be disabled, allowing these pins to be used as GPIO instead.

Figure 9-1. JTAG Interface Connections between PSoC 3 and Programmer



¹ The voltage levels of Host Programmer and the PSoC 3 voltage domains involved in Programming should be same. The Port 1 JTAG pins, XRES pin (XRES_N or P1[2]) are powered by VDDIO1. So, VDDIO1 of PSoC 3 should be at same voltage level as host VDD. Rest of PSoC 3 voltage domains (VDD, VDDA, VDDIO0, VDDIO2, VDDIO3) need not be at the same voltage level as host Programmer.

² Vdda must be greater than or equal to all other power supplies (Vddd, Vddio's) in PSoC 3.

³ For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio's) to PSoC 3. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.

⁴ For JTAG Programming, Device reset can also be done without connecting to the XRES pin or Power cycle mode by using the TMS, TCK, TDI, TDO pins of PSoC 3, and writing to a specific register. But this requires that the DPS setting in NVL is not equal to "Debug Ports Disabled".

⁵ By default, PSoC 3 is configured for 4-wire JTAG mode unless user changes the DPS setting. So the TMS pin is unidirectional. But if the DPS setting is changed to non-JTAG mode, the TMS pin in JTAG is bi-directional as the SWD Protocol has to be used for acquiring the PSoC 3 device initially. After switching from SWD to JTAG mode, the TMS pin will be uni-directional. In such a case, unidirectional buffer should not be used on TMS line.

⁶ nTRST JTAG pin (P1[5]) cannot be used to reset the JTAG TAP controller during first time programming of PSoC 3 as the default setting is 4-wire JTAG (nTRST disabled). Use the TMS, TCK pins to do a reset of JTAG TAP controller.

⁷ If XRES pin is used by host, P1[2] will be configured as XRES by default only for 48-pin devices (without dedicated XRES pin). For devices with dedicated XRES pin, P1[2] is GPIO pin by default. So use P1[2] as Reset pin only for 48-pin devices, but use dedicated XRES pin for rest of devices.

9.3 Debug Features

Using the JTAG or SWD interface, the CY8C36 supports the following debug features:

- Halt and single-step the CPU
- View and change CPU and peripheral registers, and RAM addresses
- Eight program address breakpoints
- One memory access breakpoint—break on reading or writing any memory address and data value
- Break on a sequence of breakpoints (non recursive)
- Debugging at the full speed of the CPU
- Compatible with PSoC Creator and MiniProg3 programmer and debugger
- Standard JTAG programming and debugging interfaces make CY8C36 compatible with other popular third-party tools (for example, ARM / Keil)

9.4 Trace Features

The CY8C36 supports the following trace features when using JTAG or SWD:

- Trace the 8051 program counter (PC), accumulator register (ACC), and one SFR / 8051 core RAM register
- Trace depth up to 1000 instructions if all registers are traced, or 2000 instructions if only the PC is traced (on devices that include trace memory)
- Program address trigger to start tracing
- Trace windowing, that is, only trace when the PC is within a given range
- Two modes for handling trace buffer full: continuous (overwriting the oldest trace data) or break when trace buffer is full

9.5 Single Wire Viewer Interface

The SWV interface is closely associated with SWD but can also be used independently. SWV data is output on the JTAG interface's TDO pin. If using SWV, you must configure the device for SWD, not JTAG. SWV is not supported with the JTAG interface.

SWV is ideal for application debug where it is helpful for the firmware to output data similar to 'printf' debugging on PCs. The SWV is ideal for data monitoring, because it requires only a single pin and can output data in standard UART format or Manchester encoded format. For example, it can be used to tune a PID control loop in which the output and graphing of the three error terms greatly simplifies coefficient tuning.

The following features are supported in SWV:

- 32 virtual channels, each 32 bits long
- Simple, efficient packing and serializing protocol
- Supports standard UART format (N81)

9.6 Programming Features

The JTAG and SWD interfaces provide full programming support. The entire device can be erased, programmed, and verified. You can increase flash protection levels to protect firmware IP. Flash protection can only be reset after a full device erase. Individual flash blocks can be erased, programmed, and verified, if block security settings permit.

9.7 Device Security

PSoC 3 offers an advanced security feature called device security, which permanently disables all test, programming, and debug ports, protecting your application from external access. The device security is activated by programming a 32-bit key (0x50536F43) to a Write Once Latch (WOL).

The WOL is a type of nonvolatile latch (NVL). The cell itself is an NVL with additional logic wrapped around it. Each WOL device contains four bytes (32 bits) of data. The wrapper outputs a '1' if a super-majority (28 of 32) of its bits match a pre-determined pattern (0x50536F43); it outputs a '0' if this majority is not reached. When the output is 1, the Write Once NV latch locks the part out of Debug and Test modes; it also permanently gates off the ability to erase or alter the contents of the latch. Matching all bits is intentionally not required, so that single (or few) bit failures do not deassert the WOL output. The state of the NVL bits after wafer processing is truly random with no tendency toward 1 or 0.

The WOL only locks the part after the correct 32-bit key (0x50536F43) is loaded into the NVL's volatile memory, programmed into the NVL's nonvolatile cells, and the part is reset. The output of the WOL is only sampled on reset and used to disable the access. This precaution prevents anyone from reading, erasing, or altering the contents of the internal memory.

The user can write the key into the WOL to lock out external access only if no flash protection is set (see "Flash Security" on page 23). However, after setting the values in the WOL, a user still has access to the part until it is reset. Therefore, a user can write the key into the WOL, program the flash protection data, and then reset the part to lock it.

If the device is protected with a WOL setting, Cypress cannot perform failure analysis and, therefore, cannot accept RMAs from customers. The WOL can be read out through the SWD port to electrically identify protected parts. The user can write the key in WOL to lock out external access only if no flash protection is set. For more information on how to take full advantage of the security features in PSoC see the PSoC 3 TRM.

Disclaimer

Note the following details of the flash code protection features on Cypress devices.

Cypress products meet the specifications contained in their particular Cypress data sheets. Cypress believes that its family of products is one of the most secure families of its kind on the market today, regardless of how they are used. There may be methods, unknown to Cypress, that can breach the code protection features. Any of these methods, to our knowledge, would be dishonest and possibly illegal. Neither Cypress nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not mean that we are guaranteeing the product as "unbreakable."

Cypress is willing to work with the customer who is concerned about the integrity of their code. Code protection is constantly evolving. We at Cypress are committed to continuously improving the code protection features of our products.

11. Electrical Specifications

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted. The unique flexibility of the PSoC UDBs and analog blocks enable many functions to be implemented in PSoC Creator components, see the component data sheets for full AC/DC specifications of individual functions. See the “[Example Peripherals](#)” section on page 44 for further explanation of PSoC Creator components.

11.1 Absolute Maximum Ratings

Table 11-1. Absolute Maximum Ratings DC Specifications^[22]

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{DDA}	Analog supply voltage relative to V_{SSA}		-0.5	–	6	V
V_{DDD}	Digital supply voltage relative to V_{SSD}		-0.5	–	6	V
V_{DDIO}	I/O supply voltage relative to V_{SSD}		-0.5	–	6	V
V_{CCA}	Direct analog core voltage input		-0.5	–	1.95	V
V_{CCD}	Direct digital core voltage input		-0.5	–	1.95	V
V_{SSA}	Analog ground voltage		$V_{SSD} - 0.5$	–	$V_{SSD} + 0.5$	V
$V_{GPIO}^{[23]}$	DC input voltage on GPIO	Includes signals sourced by V_{DDA} and routed internal to the pin	$V_{SSD} - 0.5$	–	$V_{DDIO} + 0.5$	V
V_{SIO}	DC input voltage on SIO	Output disabled	$V_{SSD} - 0.5$	–	7	V
		Output enabled	$V_{SSD} - 0.5$	–	6	V
V_{IND}	Voltage at boost converter input		0.5	–	5.5	V
V_{BAT}	Boost converter supply		$V_{SSD} - 0.5$	–	5.5	V
I_{VDDIO}	Current per V_{DDIO} supply pin		–	–	100	mA
I_{GPIO}	GPIO current		-30	–	41	mA
I_{SIO}	SIO current		-49	–	28	mA
I_{USBIO}	USBIO current		-56	–	59	mA
V_{EXTREF}	ADC external reference inputs	Pins P0[3], P3[2]	–	–	2	V
LU	Latch up current ^[24]		-140	–	140	mA
ESD_{HBM}	Electrostatic discharge voltage, Human body model	V_{SSA} tied to V_{SSD}	2200	–	–	V
		V_{SSA} not tied to V_{SSD}	750	–	–	V
ESD_{CDM}	Electrostatic discharge voltage, Charge device model		500	–	–	V

Notes

22. Usage above the absolute maximum conditions listed in [Table 11-1](#) may cause permanent damage to the device. Exposure to Absolute Maximum conditions for extended periods of time may affect device reliability. The Maximum Storage Temperature is 150 °C in compliance with JEDEC Standard JESD22-A103, High Temperature Storage Life. When used below Absolute Maximum conditions but above normal operating conditions, the device may not operate to specification.

23. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin $\leq V_{DDIO} \leq V_{DDA}$.

24. Meets or exceeds JEDEC Spec EIA/JESD78 IC Latch-up Test.

11.2 Device Level Specifications

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.2.1 Device Level Specifications

Table 11-2. DC Specifications

Parameter	Description	Conditions	Min	Typ ^[29]	Max	Units
V _{DDA}	Analog supply voltage and input to analog core regulator	Analog core regulator enabled	1.8	–	5.5	V
V _{DDA}	Analog supply voltage, analog regulator bypassed	Analog core regulator disabled	1.71	1.8	1.89	V
V _{DDD}	Digital supply voltage relative to V _{SSD}	Digital core regulator enabled	1.8	–	V _{DDA} ^[25]	V
			–	–	V _{DDA} + 0.1 ^[31]	
V _{DDD}	Digital supply voltage, digital regulator bypassed	Digital core regulator disabled	1.71	1.8	1.89	V
V _{DDIO} ^[26]	I/O supply voltage relative to V _{SSIO}		1.71	–	V _{DDA} ^[25]	V
			–	–	V _{DDA} + 0.1 ^[31]	
V _{CCA}	Direct analog core voltage input (Analog regulator bypass)	Analog core regulator disabled	1.71	1.8	1.89	V
V _{CCD}	Direct digital core voltage input (Digital regulator bypass)	Digital core regulator disabled	1.71	1.8	1.89	V
I _{DD} ^[27, 28]	Active Mode					
	Only IMO and CPU clock enabled. CPU executing simple loop from instruction buffer.	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 6 MHz ^[30]	T = –40 °C	–	1.2	mA
			T = 25 °C	–	1.2	
			T = 85 °C	–	4.9	
	IMO enabled, bus clock and CPU clock enabled. CPU executing program from flash.	V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 3 MHz ^[30]	T = –40 °C	–	1.3	
			T = 25 °C	–	1.6	
			T = 85 °C	–	4.8	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 6 MHz	T = –40 °C	–	2.1	
			T = 25 °C	–	2.3	
			T = 85 °C	–	5.6	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 12 MHz ^[30]	T = –40 °C	–	3.5	
			T = 25 °C	–	3.8	
			T = 85 °C	–	7.1	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 24 MHz ^[30]	T = –40 °C	–	6.3	
			T = 25 °C	–	6.6	
			T = 85 °C	–	10	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 48 MHz ^[30]	T = –40 °C	–	11.5	
			T = 25 °C	–	12	
			T = 85 °C	–	15.5	
		V _{DDX} = 2.7 V – 5.5 V; F _{CPU} = 62 MHz	T = –40 °C	–	16	
			T = 25 °C	–	16	
			T = 85 °C	–	19.5	

Notes

25. The power supplies can be brought up in any sequence however once stable V_{DDA} must be greater than or equal to all other supplies.

26. The V_{DDIO} supply voltage must be greater than the maximum voltage on the associated GPIO pins. Maximum voltage on GPIO pin $\leq V_{DDIO} \leq V_{DDA}$.

27. Total current for all power domains: digital (I_{DD}), analog (I_{DDA}), and I/Os (I_{DDIO}, 1, 2, 3). Boost not included. All I/Os floating.

28. The current consumption of additional peripherals that are implemented only in programmed logic blocks can be found in their respective datasheets, available in PSoC Creator, the integrated design environment. To estimate total current, find the CPU current at the frequency of interest and add peripheral currents for your particular system from the device datasheet and component datasheets.

29. V_{DDX} = 3.3 V.

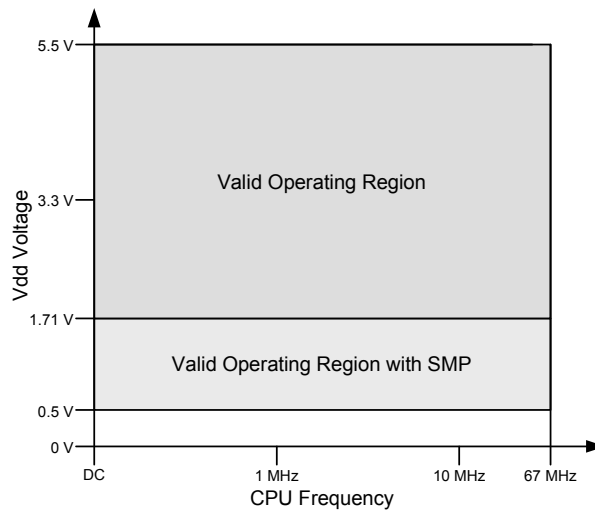
30. Based on device characterization (Not production tested).

31. Guaranteed by design, not production tested.

Table 11-3. AC Specifications^[37]

Parameter	Description	Conditions	Min	Typ	Max	Units
F _{CPU}	CPU frequency	$1.71\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	DC	–	67.01	MHz
F _{BUSCLK}	Bus frequency	$1.71\text{ V} \leq V_{DD} \leq 5.5\text{ V}$	DC	–	67.01	MHz
Svdd	V _{DD} ramp rate		–	–	0.066	V/μs
T _{IO_INIT}	Time from V _{DDD} /V _{DDA} /V _{CCD} /V _{CCA} ≥ IPOR to I/O ports set to their reset states		–	–	10	μs
T _{STARTUP}	Time from V _{DDD} /V _{DDA} /V _{CCD} /V _{CCA} ≥ PRES to CPU executing code at reset vector	V _{CCA} /V _{DDA} = regulated from V _{DDA} /V _{DDD} , no PLL used, fast IMO boot mode (48 MHz typ.)	–	–	40	μs
		V _{CCA} /V _{CCD} = regulated from V _{DDA} /V _{DDD} , no PLL used, slow IMO boot mode (12 MHz typ.)	–	–	74	μs
T _{SLEEP}	Wakeup from sleep mode – Application of non-LVD interrupt to beginning of execution of next CPU instruction		–	–	15	μs
T _{HIBERNATE}	Wakeup from hibernate mode – Application of external interrupt to beginning of execution of next CPU instruction		–	–	100	μs

Figure 11-4. F_{CPU} vs. V_{DD}



Note

³⁷. Based on device characterization (Not production tested).

Figure 11-11. Efficiency vs V_{BAT} , $L_{BOOST} = 4.7 \mu H$ [42]

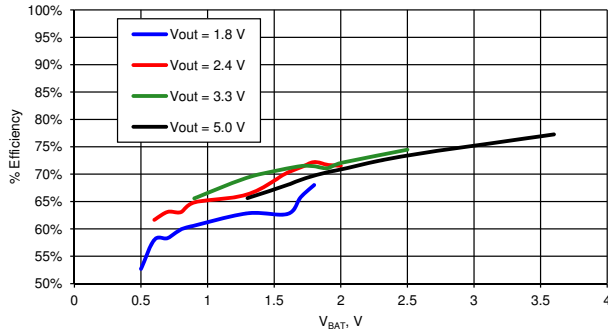


Figure 11-12. Efficiency vs V_{BAT} , $L_{BOOST} = 10 \mu H$ [42]

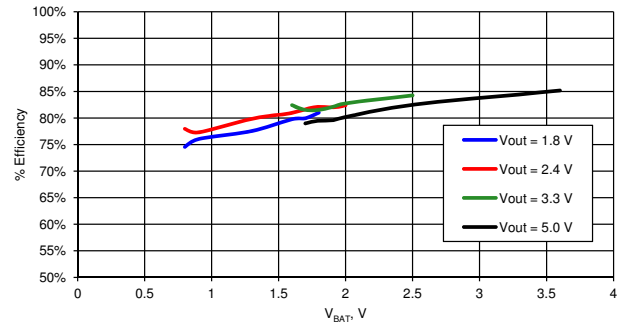


Figure 11-13. Efficiency vs V_{BAT} , $L_{BOOST} = 22 \mu H$ [42]

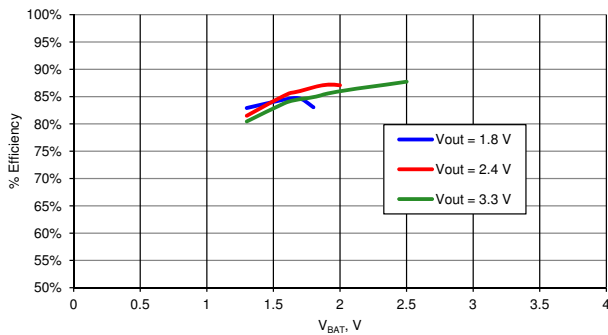
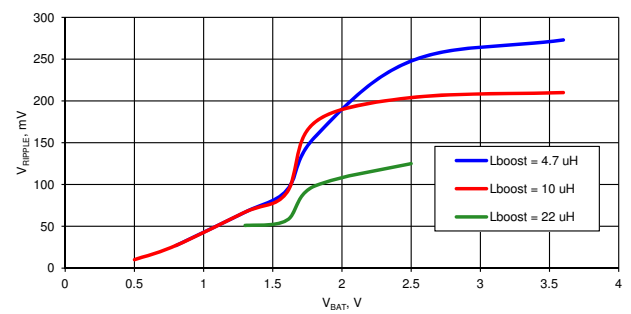


Figure 11-14. V_{RIPPLE} vs V_{BAT} [42]



Note

42. Typical example. Actual values may vary depending on external component selection, PCB layout, and other design parameters.

11.4.4 XRES

Table 11-17. XRES DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{IH}	Input voltage high threshold		$0.7 \times V_{DDIO}$	–	–	V
V _{IL}	Input voltage low threshold		–	–	$0.3 \times V_{DDIO}$	V
R _{pullup}	Pull-up resistor		3.5	5.6	8.5	kΩ
C _{IN}	Input capacitance ^[50]		–	3	–	pF
V _H	Input voltage hysteresis (Schmitt–Trigger) ^[50]		–	100	–	mV
I _{diode}	Current through protection diode to V _{DDIO} and V _{SSIO}		–	–	100	μA

Table 11-18. XRES AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T _{RESET}	Reset pulse width		1	–	–	μs

11.5 Analog Peripherals

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.5.1 Opamp

Table 11-19. Opamp DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{IOFF}	Input offset voltage		–	–	2	mV
V _{OS}	Input offset voltage		–	–	2.5	mV
		Operating temperature $-40\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	–	–	2	mV
TCV _{OS}	Input offset voltage drift with temperature	Power mode = high	–	–	±30	μV / °C
Ge1	Gain error, unity gain buffer mode	R _{load} = 1 kΩ	–	–	±0.1	%
C _{IN}	Input capacitance	Routing from pin	–	–	18	pF
V _O	Output voltage range	1 mA, source or sink, power mode = high	V _{SSA} + 0.05	–	V _{DDA} – 0.05	V
I _{OUT}	Output current capability, source or sink	V _{SSA} + 500 mV ≤ V _{out} ≤ V _{DDA} –500 mV, V _{DDA} > 2.7 V	25	–	–	mA
		V _{SSA} + 500 mV ≤ V _{out} ≤ V _{DDA} –500 mV, 1.7 V = V _{DDA} ≤ 2.7 V	16	–	–	mA
I _{DD}	Quiescent current	Power mode = min	–	250	400	μA
		Power mode = low	–	250	400	μA
		Power mode = med	–	330	950	μA
		Power mode = high	–	1000	2500	μA
CMRR	Common mode rejection ratio		80	–	–	dB
PSRR	Power supply rejection ratio	V _{DDA} ≥ 2.7 V	85	–	–	dB
		V _{DDA} < 2.7 V	70	–	–	dB
I _{IB}	Input bias current ^[50]	25 °C	–	10	–	pA

Note

50. Based on device characterization (Not production tested).

11.5.8 Mixer

The mixer is created using a SC/CT analog block; see the Mixer component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-32. Mixer DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{OS}	Input offset voltage		–	–	15	mV
	Quiescent current		–	0.9	2	mA
G	Gain		–	0	–	dB

Table 11-33. Mixer AC Specifications^[63]

Parameter	Description	Conditions	Min	Typ	Max	Units
f _{LO}	Local oscillator frequency	Down mixer mode	–	–	4	MHz
f _{in}	Input signal frequency	Down mixer mode	–	–	14	MHz
f _{LO}	Local oscillator frequency	Up mixer mode	–	–	1	MHz
f _{in}	Input signal frequency	Up mixer mode	–	–	1	MHz
SR	Slew rate		3	–	–	V/μs

11.5.9 Transimpedance Amplifier

The TIA is created using a SC/CT analog block; see the TIA component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-34. Transimpedance Amplifier (TIA) DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V _{I_{OFF}}	Input offset voltage		–	–	10	mV
R _{conv}	Conversion resistance ^[64]	R = 20K; 40 pF load	–25	–	+35	%
		R = 30K; 40 pF load	–25	–	+35	%
		R = 40K; 40 pF load	–25	–	+35	%
		R = 80K; 40 pF load	–25	–	+35	%
		R = 120K; 40 pF load	–25	–	+35	%
		R = 250K; 40 pF load	–25	–	+35	%
		R = 500K; 40 pF load	–25	–	+35	%
		R = 1M; 40 pF load	–25	–	+35	%
	Quiescent current		–	1.1	2	mA

Table 11-35. Transimpedance Amplifier (TIA) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
BW	Input bandwidth (–3 dB)	R = 20K; –40 pF load	1500	–	–	kHz
		R = 120K; –40 pF load	240	–	–	kHz
		R = 1M; –40 pF load	25	–	–	kHz

Notes

63. Based on device characterization (Not production tested).

64. Conversion resistance values are not calibrated. Calibrated values and details about calibration are provided in PSoC Creator component data sheets. External precision resistors can also be used.

11.7 Memory

Specifications are valid for $-40\text{ }^{\circ}\text{C} \leq T_A \leq 85\text{ }^{\circ}\text{C}$ and $T_J \leq 100\text{ }^{\circ}\text{C}$, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.7.1 Flash

Table 11-55. Flash DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V_{DDD} pin	1.71	–	5.5	V

Table 11-56. Flash AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Row write time (erase + program)		–	15	20	ms
T_{ERASE}	Row erase time		–	10	13	ms
	Row program time		–	5	7	ms
T_{BULK}	Bulk erase time (16 KB to 64 KB)		–	–	35	ms
	Sector erase time (8 KB to 16 KB)		–	–	15	ms
T_{PROG}	Total device programming time	No overhead ^[67]	–	1.5	2	seconds
	Flash data retention time, retention period measured from last erase cycle	Average ambient temp. $T_A \leq 55\text{ }^{\circ}\text{C}$, 100 K erase/program cycles	20	–	–	years
		Average ambient temp. $T_A \leq 85\text{ }^{\circ}\text{C}$, 10 K erase/program cycles	10	–	–	

11.7.2 EEPROM

Table 11-57. EEPROM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage		1.71	–	5.5	V

Table 11-58. EEPROM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Single row erase/write cycle time		–	10	20	ms
	EEPROM data retention time, retention period measured from last erase cycle	Average ambient temp, $T_A \leq 25\text{ }^{\circ}\text{C}$, 1M erase/program cycles	20	–	–	years
		Average ambient temp, $T_A \leq 55\text{ }^{\circ}\text{C}$, 100 K erase/program cycles	20	–	–	
		Average ambient temp. $T_A \leq 85\text{ }^{\circ}\text{C}$, 10 K erase/program cycles	10	–	–	

Note

67. See PSoC® 3 Device Programming Specifications for a low-overhead method of programming PSoC 3 flash.

Description Title: PSoC® 3: CY8C36 Family Datasheet Programmable System-on-Chip (PSoC®) (continued)
Document Number: 001-53413

Revision	ECN	Submission Date	Orig. of Change	Description of Change
*E	2938381	05/27/10	MKEA	<p>Replaced V_{DDIO} with V_{DDP} in USBIO diagram and specification tables, added text in USBIO section of Electrical Specifications.</p> <p>Added Table 13-2 (Package MSL)</p> <p>Modified Tstorag condition and changed max spec to 100</p> <p>Added bullet (Pass) under ALU (section 7.2.2.2)</p> <p>Added figures for kHzECO and MHzECO in the External Oscillator section</p> <p>Updated Figure 6-1(Clocking Subsystem diagram)</p> <p>Removed CPUCLK_DIV in table 5-2, Deleted Clock Divider SFR subsection</p> <p>Updated PSoC Creator Framework image</p> <p>Updated SIO DC Specifications (V_{IH} and V_{IL} parameters)</p> <p>Updated bullets in Clocking System and Clocking Distribution sections</p> <p>Updated Figure 8-2</p> <p>Updated PCB Layout and Schematic, updated as per MTRB review comments</p> <p>Updated Table 6-3 (power changed to current)</p> <p>In 32kHz EC DC Specifications table, changed I_{CC} Max to 0.25</p> <p>In IMO DC Specifications table, updated Supply Current values</p> <p>Updated GPIO DC Specs table</p>
*F	2958674	06/22/10	SHEA	Minor ECN to post data sheet to external website
*G	2989685	08/04/10	MKEA	<p>Added USBIO 22 ohm DP and DM resistors to Simplified Block Diagram</p> <p>Added to Table 6-6 a footnote and references to same.</p> <p>Added sentences to the resistive pull-up and pull-down description bullets.</p> <p>Added sentence to Section 6.4.11, Adjustable Output Level.</p> <p>Updated section 5.5 External Memory Interface</p> <p>Updated Table 11-73 JTAG Interface AC Specifications</p> <p>Updated Table 11-74 SWD Interface AC Specifications</p> <p>Updated style changes as per the new template.</p>
*H	3078568	11/04/10	MKEA	<p>Updated "Current Digital-to-analog Converter (IDAC)" on page 94</p> <p>Updated "Voltage Digital to Analog Converter (VDAC)" on page 99</p> <p>Updated "DC Specifications" on page 72</p> <p>Updated "Voltage Reference Specifications" on page 93</p>
*I	3107314	12/10/2010	MKEA	<p>Updated delta-sigma tables and graphs.</p> <p>Updated Flash AC specs</p> <p>Formatted table 11.2.</p> <p>Updated interrupt controller table</p> <p>Updated transimpedance amplifier section</p> <p>Updated SIO DC specs table</p> <p>Updated Voltage Monitors DC Specifications table</p> <p>Updated LCD Direct Drive DC specs table</p> <p>Replaced the Discrete Time Mixer and Continuous Time Mixer tables with Mixer DC and AC specs tables</p> <p>Updated ESD_{HBM} value.</p> <p>Updated IDAC and VDAC sections</p> <p>Removed ESO parts from ordering information</p> <p>Changed USBIO pins from NC to DNU and removed redundant USBIO pin description notes</p> <p>Updated POR with brown out DC and AC specs</p> <p>Updated PGA AC specs</p> <p>Updated 32 kHz External Crystal DC Specifications</p> <p>Updated opamp AC specs</p> <p>Updated XRES IO specs</p> <p>Updated Inductive boost regulator section</p> <p>Delta sigma ADC spec updates</p> <p>Updated comparator section</p> <p>Removed buzz mode from Power Mode Transition diagram</p> <p>Updated opamp DC and AC spec tables</p> <p>Updated PGA DC table</p>

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Revision	ECN	Submission Date	Orig. of Change	Description of Change
*M	3464258	12/14/2011	MKEA	<p>Updated Analog Global specs</p> <p>Updated IDAC range</p> <p>Updated TIA section</p> <p>Modified VDDIO description in Section 3</p> <p>Added note on Sleep and Hibernate modes in the Power Modes section</p> <p>Updated Boost Converter section</p> <p>Updated conditions for Inductive boost AC specs</p> <p>Added VDAC/IDAC noise graphs and specs</p> <p>Added pin capacitance specs for ECO pins</p> <p>Removed C_L from 32 kHz External Crystal DC Specs table.</p> <p>Added reference to AN54439 in Section 6.1.2.2</p> <p>Deleted T_SWDO_hold row from the SWD Interface AC Specifications table</p> <p>Removed Pin 46 connections in "Example Schematic for 100-pin TQFP Part with Power Connections"</p> <p>Updated Active Mode IDD description in Table 11-2.</p> <p>Added I_{DDDR} and I_{DDAR} specs in Table 11-2.</p> <p>Replaced "total device program time" with T_{PROG} in Flash AC specs table</p> <p>Added I_{GPIO}, I_{SIO} and I_{USBIO} specs in Absolute Maximum Ratings</p> <p>Added conditions to I_{CC} spec in 32 kHz External Crystal DC Specs table.</p> <p>Updated TCV_{OS} value</p> <p>Removed Boost Efficiency vs V_{OUT} graph</p> <p>Updated boost graphs</p> <p>Updated min value of GPIO input edge rate</p> <p>Removed 3.4 Mbps in UDBs from I2C section</p> <p>Updated USBIO Block diagram; added USBIO drive mode description</p> <p>Updated Analog Interconnect diagram</p> <p>Changed max IMO startup time to 12 μs</p> <p>Added note for I_{IL} spec in USBIO DC specs table</p> <p>Updated GPIO Block diagram</p> <p>Updated voltage reference specs</p> <p>Added text explaining power supply ramp up in Section 11-4.</p>

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Revision	ECN	Submission Date	Orig. of Change	Description of Change
*P	3732521	09/03/2012	MKEA	<p>Replaced I_{DDDR} and I_{DDAR} specs in Table 11-2, "DC Specifications," on page 72 that were dropped out in *N revision.</p> <p>Updated Table 11-32, "Mixer DC Specifications," on page 102, V_{OS} Max value from 10 to 15.</p> <p>Updated Table 11-21, "12-bit Delta-sigma ADC DC Specifications," on page 91, I_{DD 12} Max value from 1.4 to 1.95 mA</p> <p>Replaced PSoC® 3 Programming AN62391 with TRM in footnote #67 and "Programming, Debug Interfaces, Resources" section on page 65</p> <p>Removed Figure 11-8 (Efficiency vs Vout)</p> <p>Updated Table 11-19, "Opamp DC Specifications," on page 88, I_{DD} Quiescent current row values from 200 and 270 to 250 and 400 respectively.</p> <p>Updated conditions for Storage Temperature in Table 11-1, "Absolute Maximum Ratings DC Specifications[22]," on page 71.</p> <p>Updated conditions and min values for NVL data retention time in Table 11-60, "NVL AC Specifications," on page 110.</p> <p>Updated Table 11-75, "ILO DC Specifications," on page 118.</p> <p>Removed the following pruned parts from the ordering information table. CY8C3665AXI-010 CY8C3665AXI-016 CY8C3665LTI-044 CY8C3665LTI-006 CY8C3665PVI-007 CY8C3665PVI-080</p> <p>Updated PSoC 3 boost circuit value throughout the document.</p> <p>Removed 100 kHz sub row in Table 11-51, "DFB DC Specifications," on page 107.</p> <p>Updated package diagram 51-85061 to *F revision.</p>
*Q	3922905	03/25/2013	MKEA	<p>Updated I_{DD XX} parameters under Table 11-21, "12-bit Delta-sigma ADC DC Specifications," on page 91.</p> <p>Updated Temperature Drift specification in Voltage Reference Specifications.</p> <p>Added CY8C3665AXI-198, CY8C3665LTI-044, CY8C3665LTI-199, CY8C3666AXI-200, CY8C3666LTI-201, CY8C3666AXI-202, and CY8C3666LTI-203 part numbers in Ordering Information.</p> <p>Updated I²C section and GPIO and SIO DC specifications tables.</p> <p>Corrected Hibernate max limit.</p> <p>Changed INL max value from ±1.5 to ±1.6 in IDAC DC Specifications.</p> <p>Updated ECCEN default setting in Fields and Factory Default Settings.</p>
*R	4064707	07/18/2013	MKEA	<p>Added USB test ID in Features.</p> <p>Updated schematic in Section 2..</p> <p>Added paragraph for device reset warning in Section 5.4.</p> <p>Added NVL bit for DEBUG_EN in Section 5.5.</p> <p>Updated UDB PLD array diagram in Section 7.2.1.</p> <p>Changed Tstartup specs in Section 11.2.1.</p> <p>Changed GPIO rise and fall time specs in Section 11.4.</p> <p>Added Opamp I_{IB} spec in Section 11.5.1.</p> <p>Added VREF spec condition: pre-assembly and added "box method" to VREF temperature drift spec conditions in Section 11.5.3.</p> <p>Added IMO spec condition: pre-assembly in Section 11.9.1.</p> <p>Added Appendix for CSP package (preliminary)</p>
*S	4118845	09/10/2013	MKEA	<p>Removed T_{STG} spec and added note clarifying maximum storage temperature range in Table 11-1.</p> <p>Updated Vos spec conditions and TCvos in Table 11-21.</p> <p>Updated F_{IMO} spec (3 MHz).</p> <p>Updated 100-TQFP package diagram.</p>